

Notice of References Cited	Application/Control No. 09/159,569	Applicant(s)/Patent Under Reexamination SUZUKI ET AL.	
	Examiner Jason T. Whipkey	Art Unit 2612	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,973,311	10-1999	Sauer et al.	348/302
	B	US-5,898,168	04-1999	Gowda et al.	348/311
	C	US-4,621,291	11-1986	Takemoto et al.	348/303
	D	US-5,001,359	03-1991	Hashimoto et al.	348/241
	E	US-6,320,618	11-2001	Aoyama, Chiaki	348/335
	F	US-6,037,577	03-2000	Tanaka et al.	348/302
	G	US-5,831,258	11-1998	Street, Robert A.	348/308
	H	US-4,547,806	10-1985	Herbst et al.	348/300
	I	US-5,543,838	08-1996	Hosier et al.	348/303
	J	US-5,978,025	11-1999	Tomasini et al.	348/308
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 10248034 A1	09-1998	Japan	Tronnamuchai	--
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ozaki, Toshifumi et al. "A Low-Noise Line-Amplified MOS Imaging Devices." IEEE Transactions on Electron Devices, Vol. 38, No. 5, May 1991. 969-975.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.